

Notice of References Cited	Application/Control No. 10/563,315	Applicant(s)/Patent Under Reexamination IWATSU ET AL.	
	Examiner Bobbak Safaipoor	Art Unit 2618	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,084,906 A	07-2000	Kao et al.	375/220
*	B	US-6,160,988 A	12-2000	Shroyer, Stephen R.	725/63
*	C	US-2002/0016178 A1	02-2002	Kito, Eiji	455/522
*	D	US-2002/0105962 A1	08-2002	Bolgiano et al.	370/442
*	E	US-6,584,086 B1	06-2003	Shim et al.	370/335
*	F	US-2003/0181160 A1	09-2003	Hirsch, Andrew J.	455/3.02
*	G	US-2003/0211843 A1	11-2003	Song et al.	455/411
*	H	US-2005/0186983 A1	08-2005	Iochi, Hitoshi	455/522
*	I	US-2006/0190796 A1	08-2006	Hagiwara et al.	714/749
*	J	US-2006/0221932 A1	10-2006	Iwatsu et al.	370/352
*	K	US-2006/0251079 A1	11-2006	Kwak et al.	370/394
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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